

Search Notes

Application/Control No.

10/006,046

Examiner

Hanh Nguyen

Applicant(s)/Patent under
Reexamination

LEWIS, MICHAEL E.

Art Unit

370

SEARCHED

Class	Subclass	Date	Examiner
370	329	1/3/2007	HN
	337		
	321		
	458		
	336		
455	450		
	453		
	509		
	516		
370	468		
	395.4		

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner
370	310.2	1/3/2007	HN
	341		
455	63.4		

**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
east	1/3/2007	HN